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Table of contents

Volume 304

EMAS 2017 Workshop - 15th European Workshop on Modern Developments and Applications in Microbeam Analysis & IUMAS-7 Meeting - 7th Meeting of the International union of Microbeam Analysis Societies

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Preface

EMAS 2017 Workshop - 15th European Workshop on Modern Developments and Applications in Microbeam Analysis & IUMAS-7 Meeting - 7th Meeting of the International union of Microbeam Analysis Societies

Peer review statement

Papers

Trace element analysis by EPMA in geosciences: detection limit, precision and accuracy

V G Batanova, A V Sobolev and V Magnin....1

Measurements of the quantitative lateral analytical resolution at evaporated aluminium and silver layers with the JEOL JXA-8530F FEG-EPMA

D Berger and J Nissen.....18

<u>Understanding deformation with high angular resolution electron backscatter diffraction</u> (HR-EBSD)

T B Britton and J L R Hickey.....28

A deterministic model of electron transport for electron probe microanalysis

J Bünger, S Richter and M Torrilhon.....41

Benefits from bremsstrahlung distribution evaluation to get unknown information from specimen in SEM and TEM

F Eggert, P P Camus, M Schleifer and F Reinauer.....53

Development of a compact FE-SEM and X-ray microscope with a carbon nanotube electron source

M Irita, S Yamazaki, H Nakahara and Y Saito.....67

Focussed ion beam thin sample microanalysis using a field emission gun electron probe microanalyser

Y Kubo.....73

Microscopic stress characterisation of functional iron-based alloys by white X-ray microbeam diffraction

E P Kwon, S Sato, S Fujieda, K Shinoda, K Kajiwara, M Sato and S Suzuki.....85

Influence of simulation parameters on the speed and accuracy of Monte Carlo calculations using PENEPMA

X Llovet and F Salvat.....94

Soft X-ray and cathodoluminescence measurement, optimisation and analysis at liquid nitrogen temperatures

C M MacRae, N C Wilson, A Torpy and C Delle Piane.....106

In-situ TEM study on structural change and light emission of a multiwall carbon nanotube during Joule heating

K Nishikawa, K Asaka, H Nakahara and Y Saito.....120

Secondary fluorescence near phase boundaries - Typical cases in steel

M R Rijnders and C J G van Hoek.....125

Exploring the limits of EDS microanalysis: rare earth element analyses

N W M Ritchie, D E Newbury, H Lowers and M Mengason.....132

Monte Carlo simulation and fundamental quantities

F Salvat and X Llovet.....142

A tracking algorithm for Monte Carlo simulation of surface roughness in EPMA measurements

D Sánchez-Gonzalo, X Llovet, R Graciani and F Salvat.....157

Calculation of catalyst crust thickness from full elemental laser-induced breakdown spectroscopy images

L Sorbier, F Trichard, S Moncayo, C P Lienemann and V Motto-Ros.....167

A convenient method for X-ray analysis in TEM that measures mass thickness and composition

P Statham, J Sagar, J Holland, P Pinard and S. Lozano-Perez.....177

Information observed in Ti-L α , β and Ti-L ℓ , η emission lines of Ti and its oxides

M Terauchi, S Koshiya and K Kimito.....183

Monte Carlo simulation of the effect of shape and thickness on SEM-EDS microanalysis of asbestos fibres and bundles: the case of anthophyllite, tremolite and actinolite

G Valdrè, D Moro and G Ulian.....189

<u>Synthesis and characterisation of PuPO₄ - a potential analytical standard for EPMA actinide quantification</u>

K E Wright, K Popa and P Pöml.....200

A new life for the wavelength-dispersive X-ray spectrometer (WDS): incorporation of a silicon drift detector into the WDS for improved quantification and X-ray mapping

R Wuhrer and K Moran.....206